Nondestructive Testing for SCC Colony Mapping and Crack Depth Sizing

Advanced Eddy-Current Crack Imaging & Depth Sizing Capability with MWM®-Arrays
MWM-Array Scanners for SCC Detection through Coatings
- Wide-area scanning arrays for preliminary screening of SCC through coatings (coal tar wrap, epoxy, etc.)
- Scan rates over 20 sq. ft./min (1.86 m²) using JENTEK's GridStation® 8200 instrumentation

MWM-Array Scanners for SCC Crack Mapping & Sizing
- High-resolution crack mapping and depth sizing for SCC colonies
- Conformable MWM-Array eddy current sensors for rapid C-Scan imaging
- Minimal surface preparation

Left: MWM-Array probe with FA24 sensor at field site; Middle: Adaptable MWM-Array scanner; Right: MWM-Array image of a pipeline section with SCC damage.

Crack Depth Software Module – JENTEK GridStation® software
- Rapid conversion of MWM-Array response into depth measurements
- Automatic crack interaction capability
- Electronic storage and retrieval of measurement data
- Microsoft Windows™ environment with GridStation software for easy report generation

JENTEK GridStation advanced eddy-current inspection systems have been called “the gold standard” of inspections at U.S. Navy Depots

For more information, please visit us at www.jenteksensors.com